

<b>Notice of References Cited</b>	Application/Control No. 10/584,218	Applicant(s)/Patent Under Reexamination MIYACHI ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0166409	08-2004	Takada et al.	429/218.1
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 1231654 A1	08-2002	European Patent	IKEDA et al.	
	O					
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	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Machine translation of JP 09245771 A, Inoue et al., 09/1997
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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